

20V N+N-Channel Enhancement Mode MOSFET

Description

The AP8805DF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 20V$ $I_D = 52A$

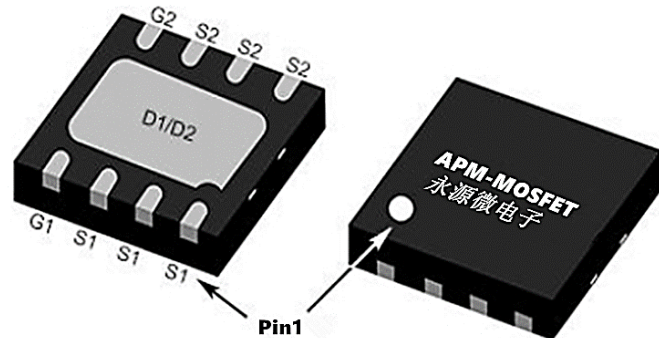
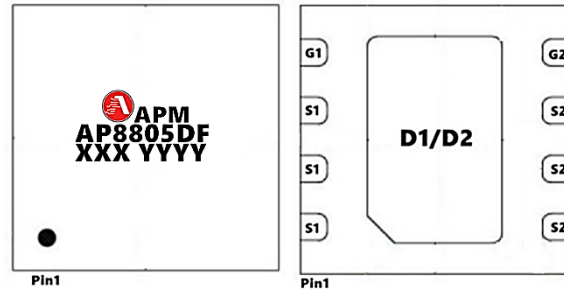
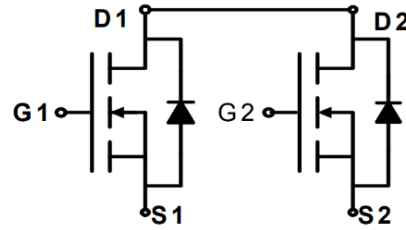
$R_{DS(ON)} < 6.0m\Omega$ @ $V_{GS}=4.5V$ (Type: 4.8m Ω)

Application

3.3V MCU Drive

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

| Product ID | Pack | Marking | Qty(PCS) |
|------------|-----------|-------------------|----------|
| AP8805DF | DFN3*3-8L | AP8805DF XXX YYYY | 5000 |

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Max. | Units |
|----------------------------|-----------------------------------------------------|-------------|---------------------------|
| V_{DS} | Drain-Source Voltage | 20 | V |
| V_{GS} | Gate-Source Voltage | ± 12 | V |
| $I_D@T_A=25^\circ\text{C}$ | Continuous Drain Current, $V_{GS} @ 4.5V$ | 52 | A |
| $I_D@T_A=70^\circ\text{C}$ | Continuous Drain Current, $V_{GS} @ 4.5V$ | 30 | A |
| I_{DM} | Pulsed Drain Current <small>note1</small> | 120 | A |
| E_{AS} | Single Pulsed Avalanche Energy <small>note2</small> | 147.6 | mJ |
| $PD@T_A=25^\circ\text{C}$ | Power Dissipation | 37 | W |
| T_J, T_{STG} | Operating and Storage Temperature Range | -55 to +175 | $^\circ\text{C}$ |
| $R_{\theta JA}$ | Thermal Resistance Junction-Ambient ¹ | 85 | $^\circ\text{C}/\text{W}$ |
| $R_{\theta JC}$ | Thermal Resistance, Junction to Case | 2 | $^\circ\text{C}/\text{W}$ |

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Electrical Characteristics (T_J=25 °C, unless otherwise noted)

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|------------------|----------------------------------------------------------|----------------------------------------------------------------------------------------------|------|------|------|------|
| V(BR)DSS | Drain-Source Breakdown Voltage | I _D = 250μA, V _{GS} = 0V | 20 | 21 | - | V |
| IDSS | Zero Gate Voltage Drain Current | V _{DS} = 20V, V _{GS} = 0V | - | - | 1.0 | μA |
| IGSS | Gate-Body Leakage Current | V _{DS} = 0V, V _{GS} = ±12V | - | - | ±100 | nA |
| VGS(th) | Gate Threshold Voltage | V _{DS} = V _{GS} , I _D = 250μA | 0.5 | 0.8 | 1.1 | V |
| RDS(ON) | Static Drain-Source ON | V _{GS} = 4.5V, I _D = 30A | - | 4.8 | 6.0 | mΩ |
| | | V _{GS} = 2.5V, I _D = 20A | - | 5.3 | 7.0 | mΩ |
| C _{iss} | Input Capacitance | V _{GS} =0V, V _{DS} =10V, f=1MHz | - | 2174 | - | pF |
| C _{oss} | Output Capacitance | | - | 396 | - | pF |
| C _{rss} | Reverse Transfer Capacitance | | - | 365 | - | pF |
| Q _g | Total Gate Charge | V _{GS} =0 to 4.5V V _{DD} =10V, I _D =30A | - | 36 | - | nC |
| Q _{gs} | Gate Source Charge | | - | 6 | - | nC |
| Q _{gd} | Gate Drain("Miller") Charge | | - | 10 | - | nC |
| td(on) | Turn-On DelayTime | V _{GS} = 4.5V, V _{DD} = 10V I _D = 30A, R _{GEN} = 3Ω | - | 13 | - | ns |
| t _r | Turn-On Rise Time | | - | 31 | - | ns |
| td(off) | Turn-Off DelayTime | | - | 73 | - | ns |
| t _f | Turn-Off Fall Time | | - | 92 | - | ns |
| IS | Maximum Continuous Drain to Source Diode Forward Current | | - | - | 70 | A |
| ISM | Maximum Pulsed Drain to Source Diode Forward Current | | - | - | 300 | A |
| V _{SD} | Drain to Source Diode Forward Voltage | V _{GS} = 0V, I _S = 30A | - | - | 1.2 | V |
| t _{rr} | Body Diode Reverse Recovery Time | I _F =20A, di/dt=100A/μs | - | 13 | - | ns |
| Q _{rr} | Body Diode Reverse Recovery Charge | | - | 4 | - | nC |

Note :

- 1、 The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、 The test condition is T_J=25°C, V_{DD}=10V, V_G=4.5V, L=0.5mH, R_G=25Ω, I_{AS}=12A
- 4、 The power dissipation is limited by 150°C junction temperature
- 5、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics

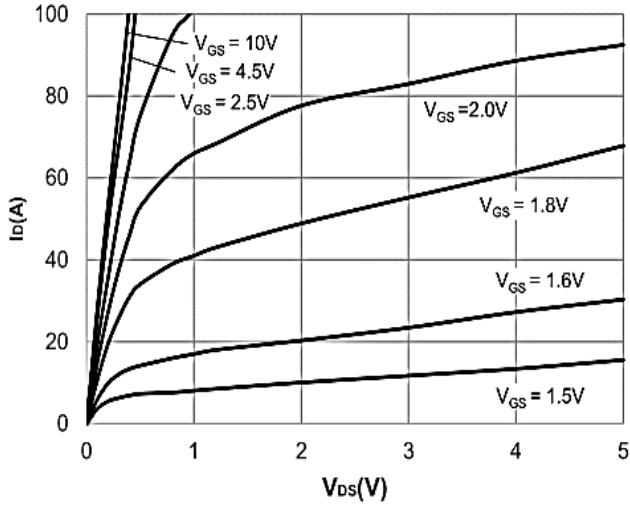


Figure 1: Output Characteristics

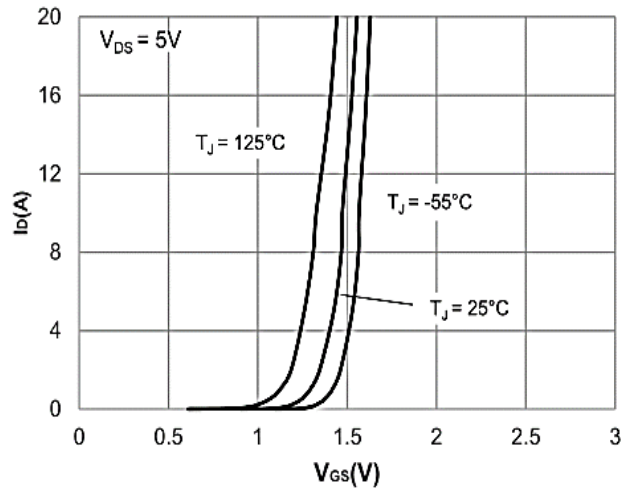


Figure 2: Typical Transfer Characteristics

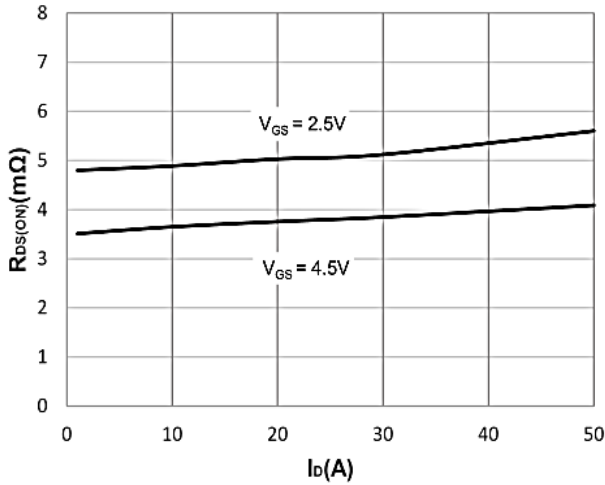


Figure 3: On-resistance vs. Drain Current

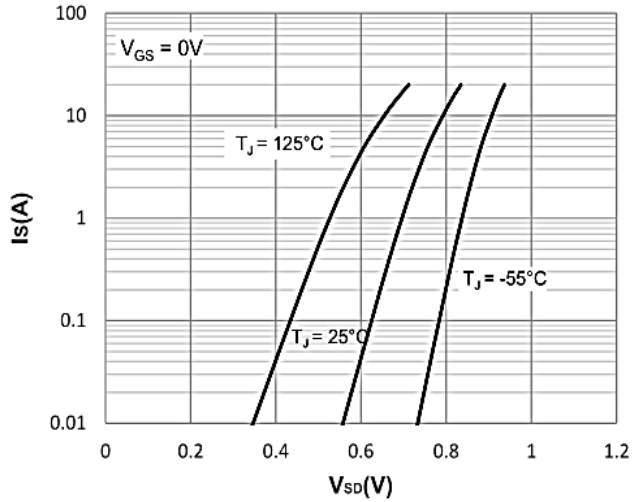


Figure 4: Body Diode Characteristics

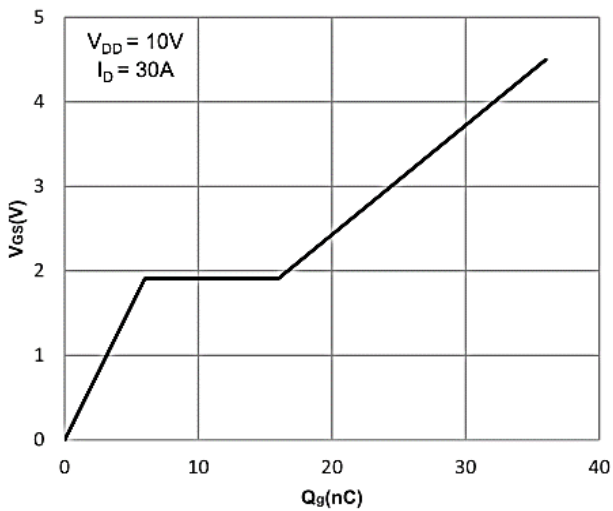


Figure 5: Gate Charge Characteristics

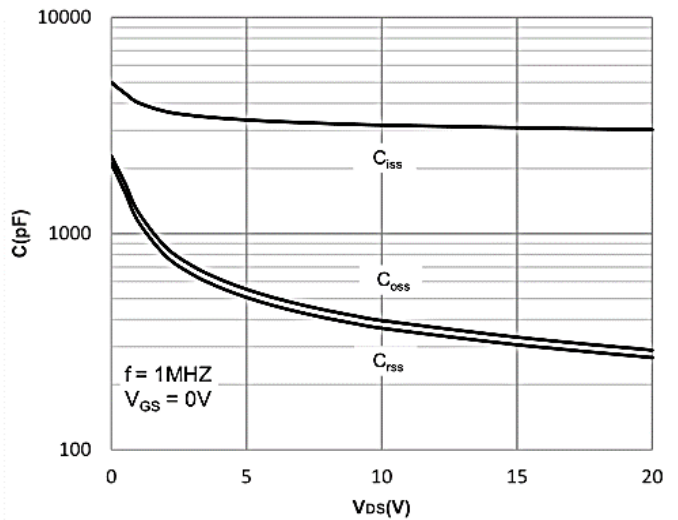


Figure 6: Capacitance Characteristics



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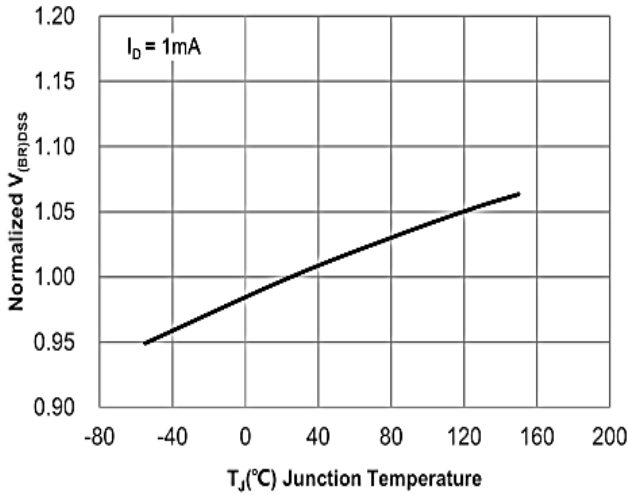


Figure 7: Normalized Breakdown Voltage vs Junction Temperature

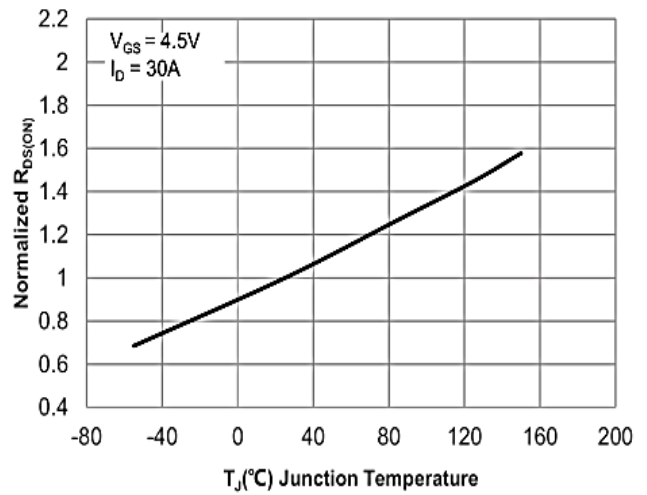


Figure 8: Normalized on Resistance vs. Junction Temperature

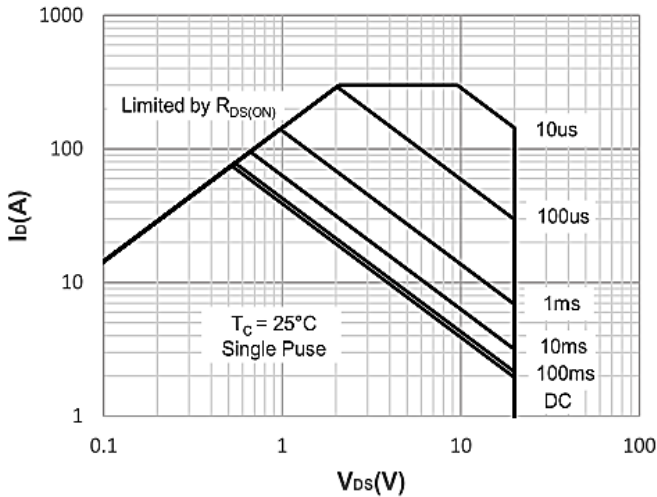


Figure 9: Maximum Safe Operating Area

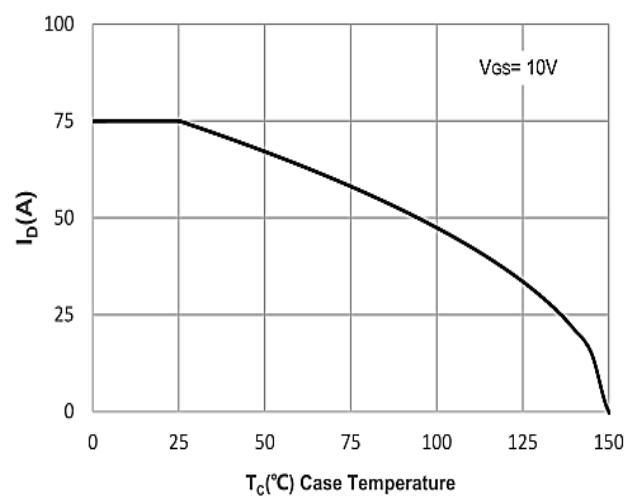


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

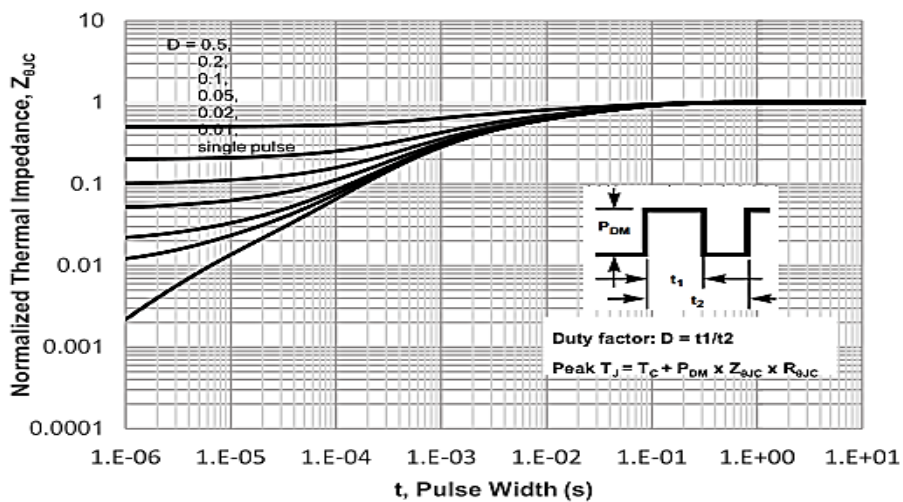
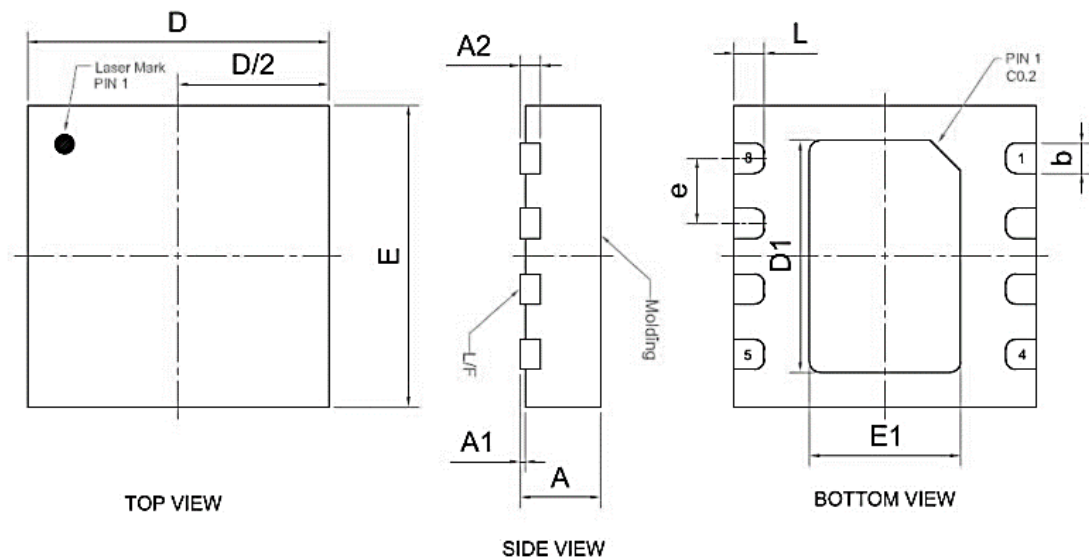


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambien

Package Mechanical Data-DFN3X3-8L


| Symbol | Dim in mm | |
|--------|-----------|------|
| | Min | Max |
| A | 0.70 | 0.80 |
| A1 | 0.00 | 0.05 |
| A2 | 0.203REF | |
| b | 0.25 | 0.35 |
| D | 2.90 | 3.10 |
| E | 2.90 | 3.10 |
| D1 | 2.20 | 2.40 |
| E1 | 1.40 | 1.60 |
| L | 0.20 | 0.40 |
| e | 0.65BSC | |

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